

Workshop

Microscopía Electrónica de Barrido (SEM) y Fuerzas Atómicas (AFM)

Martes 19
JUNIO
2018

Ubicación Centro Nacional de Investigaciones Metalúrgicas (CENIM)
Avda Gregorio del Amo 8, 28040 Madrid
Sala de Conferencias, edificio principal

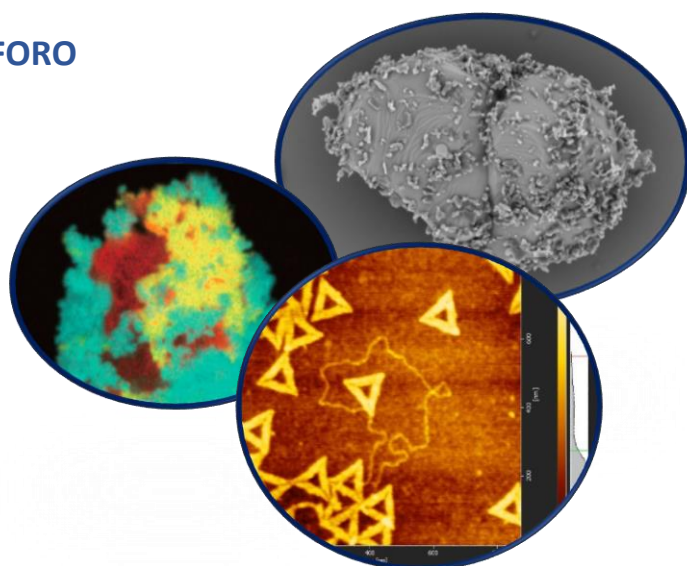


Programa:

- 9.00 – 9.30 | Breakfast/ Coffee/ Registration
- 9.30 – 9.45 | Introducción de Monocomp Instrumentación
- 9.45 – 10.30 | Basics of SEM and EDX by José Alfonso Seisdedos Bayón, Director de Monocomp Instrumentación
- 10.30 – 11.00 | Imaging surface topography: Understanding Atomic Force Microscopy (AFM) by Dr. Colin Grant, Hitachi SPM Sales & Applications Specialist
- 11.00 – 11.30 | Coffee break
- 11.30 – 12.00 | Hitachi's wide varieties of SEM sample preparation methods and its applications by Mr. Yu Sugimoto Hitachi EM Sales Manager
- 12.00 – 12.30 | Correlative Microscopy: Combined AFM & SEM for advanced materials characterisations by Dr. Colin Grant
- 12.30 – 13.15 | Hitachi's latest FE-SEM technology and its applications by Mr. Yu Sugimoto
- 13.15 – 13.30 | Q&A/ Wrap-up

**SE RUEGA CONFIRMACIÓN
ENTRADA LIBRE HASTA COMPLETAR AFORO**

Colaboran:



Contacto:

Mario Seisdedos
Tel: +34 619 135 904
mario@monocomp-instrumentacion.com

